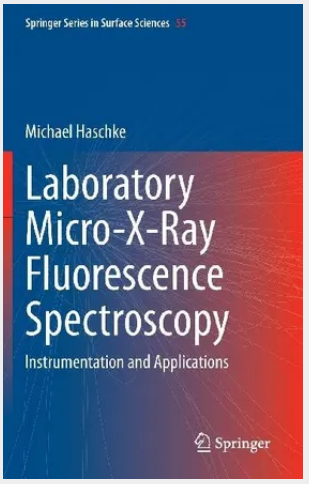
Haschke

# Laboratory Micro-X-Ray Fluorescence Spectroscopy

Instrumentation and Applications




Micro-X-ray fluorescence offers the possibility for a position- sensitive and non-destructive analysis that can be used for the analysis of non-homogeneous materials and layer systems. This analytical technique has shown a dynamic development in the last 15 years and is used for the analysis of small particles, inclusions, of elemental distributions for a wide range of different applications both in research and quality control. The first experiments were performed on synchrotrons but there is a requirement for laboratory instruments which offers a fast and immediate access for analytical results. The book discuss the main components of a µ-XRF instrument and the different measurement modes, it gives an overview about the various instruments types, considers the special requirements for quantification of non-homogeneous materials and presents a wide range of application for single point and multi-point analysis as well as for distribution analysis in one, two and three dimensions.

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**160,49 €**
149,99 € (zzgl. MwSt.)

*Lieferfrist: bis zu 10 Tage*

**Artikelnummer:** 9783319048635
**Medium:** Buch
**ISBN:** 978-3-319-04863-5
**Verlag:** Springer
**Erscheinungstermin:** 22.05.2014
**Sprache(n):** Englisch
**Auflage:** Erscheinungsjahr 2014
**Serie:** Springer Series in Surface Sciences
**Produktform:** Gebunden
**Gewicht:** 677 g
**Seiten:** 356
**Format (B x H):** 160 x 241 mm



**Kundenservice Verlag Dr. Otto Schmidt KG**
Neumannstraße 10, 40235 Düsseldorf | kundenservice@otto-schmidt.de | 0221-93738-997 (Inland)